



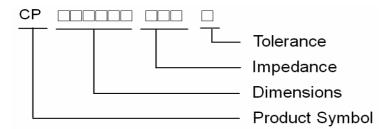
.Features:

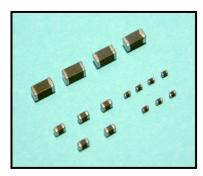
- 1. Closed magnetic circuit structure allows high density mounting while preventing crosstalk.
- 2. Extremely high reliability due to entirely monolithic construction.
- 3.Low DC resistance structure of electrode to prevent wasteful electric power consumption.
- 4. Hing Current rating up to 6A.
- 5. The products contain no lead and also support lead-free soldering.

.Applications:

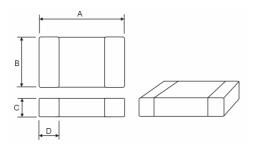
CP type has a large current funtion for power line due to its low DC resistance, it can generate an impedance down to relative low frequency and cover a wide range of noise suppression.

.Product Identification :

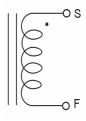




${\color{red} oxtimes}$.Shape and Dimension



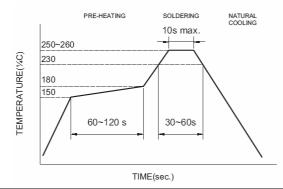




Dimensions in mm

TYPE	A(mm)	B(mm)	C(mm)	D(mm)			
CP160808	1.6±0.2 0.8±0.		0.8±0.2	0.3±0.2			
CP201209	01209 2.0±0.2 1.2		0.9±0.2	0.5±0.3			
CP321611	3.2±0.2 1.6±0.2		1.1±0.2	0.5±0.3			
CP451616	4.5±0.2	1.6±0.2	1.6±0.2	0.5±0.3			
CP453215	4.5±0.2	3.2±0.2	1.5±0.2	0.5±0.3			

.Recommended Reflow







I . Electrical Characteristics (CP160808 TYPE)

Part No.	IMPEDANCE	Test frequency	DCR	Rate Current	
Fait NO.	(Ω±25%)		(Ω) Max	(mA) Max	
CP160808T-100	10	100 MHZ,200 mV	0.02	4000	
CP160808T-110	11	100 MHZ,200 mV	0.02	4000	
CP160808T-190□	19	100 MHZ,200 mV	0.03	3000	
CP160808T-200	20	100 MHZ,200 mV	0.03	3000	
CP160808T-220	22	100 MHZ,200 mV	0.03	3000	
CP160808T-250	25	100 MHZ,200 mV	0.03	3000	
CP160808T-300	30	100 MHZ,200 mV	0.03	3000	
CP160808T-310	31	100 MHZ,200 mV	0.035	3000	
CP160808T-400□	40	100 MHZ,200 mV	0.035	3000	
CP160808T-470□	47	100 MHZ,200 mV	0.04	3000	
CP160808T-500	50	100 MHZ,200 mV	0.04	3000	
CP160808T-560	56	100 MHZ,200 mV	0.04	3000	
CP160808T-600	60	100 MHZ,200 mV	0.04	3000	
CP160808T-680	68	100 MHZ,200 mV	0.05	2500	
CP160808T-700	70	100 MHZ,200 mV	0.05	2500	
CP160808T-750	75	100 MHZ,200 mV	0.05	2500	
CP160808T-800	80	100 MHZ,200 mV	0.05	2500	
CP160808T-900	90	100 MHZ,200 mV	0.05	2500	
CP160808T-101	100	100 MHZ,200 mV	0.05	2500	
CP160808T-121	120	100 MHZ,200 mV	0.08	2500	
CP160808T-151	150	100 MHZ,200 mV	0.085	2000	
CP160808T-181	180	100 MHZ,200 mV	0.09	2000	
CP160808T-201	200	100 MHZ,200 mV	0.095	2000	
CP160808T-221	220	100 MHZ,200 mV	0.1	2000	
CP160808T-241	240	100 MHZ,200 mV	0.12	1500	
CP160808T-301	300	100 MHZ,200 mV	0.12	1500	
CP160808T-331	330	100 MHZ,200 mV	0.12	1500	
CP160808T-401□	400	100 MHZ,200 mV	0.12	1500	
CP160808T-471□	470	100 MHZ,200 mV	0.15	1500	
CP160808T-501	500	100 MHZ,200 mV	0.15	1200	
CP160808T-601	600	100 MHZ,200 mV	0.2	1000	
CP160808T-751	750	100 MHZ,200 mV	0.25	800	
CP160808T-102	1000	100 MHZ,200 mV	0.25	800	
CP160808T-152	1500	100 MHZ,200 mV	0.4	500	

Electrical Characteristics (CP201209 TYPE)

Part No.	IMPEDANCE	Test frequency	DCR	Rate Current
Fait NO.	(Ω±25%)		(Ω) Max	(mA) Max
CP201209T-050	5	100 MHZ,200 mV	0.01	6000
CP201209T-070	CP201209T-070□ 7		0.01	6000





Multilayer Chip Beads / CP TYPE (Large Current) Electrical Characteristics (CP201209 TYPE)

Part No.	IMPEDANCE	Test frequency	DCR	Rate Current	
	(Ω±25%)		(Ω) Max	(mA) Max	
CP201209T-110□	11	100 MHZ,200 mV	0.01	6000	
CP201209T-130□	13	100 MHZ,200 mV	0.02	5000	
CP201209T-150	15	100 MHZ,200 mV	0.02	5000	
CP201209T-170	17	100 MHZ,200 mV	0.02	5000	
CP201209T-190	19	100 MHZ,200 mV	0.02	4000	
CP201209T-220	22	100 MHZ,200 mV	0.02	4000	
CP201209T-260□	26	100 MHZ,200 mV	0.02	4000	
CP201209T-280	28	100 MHZ,200 mV	0.02	4000	
CP201209T-300	30	100 MHZ,200 mV	0.02	4000	
CP201209T-310□	31	100 MHZ,200 mV	0.02	4000	
CP201209T-320□	32	100 MHZ,200 mV	0.02	4000	
CP201209T-390□	39	100 MHZ,200 mV	0.02	3000	
CP201209T-400□	40	100 MHZ,200 mV	0.02	3000	
CP201209T-420□	42	100 MHZ,200 mV	0.025	3000	
CP201209T-500	50	100 MHZ,200 mV	0.025	3000	
CP201209T-600□	60	100 MHZ,200 mV	0.03	3000	
CP201209T-700	70	100 MHZ,200 mV	0.04	3000	
CP201209T-750□	75	100 MHZ,200 mV	0.04	3000	
CP201209T-800	80	100 MHZ,200 mV	0.04	3000	
CP201209T-900	90	100 MHZ,200 mV	0.04	3000	
CP201209T-101□	100	100 MHz,200 mV	0.04	3000	
CP201209T-121	120	100 MHZ,200 mV	0.04	3000	
CP201209T-131	130	100 MHZ,200 mV	0.05	2500	
CP201209T-151	150	100 MHZ,200 mV	0.05	2500	
CP201209T-181	180	100 MHZ,200 mV	0.05	2500	
CP201209T-201	200	100 MHZ,200 mV	0.05	2500	
CP201209T-221	220	100 MHZ,200 mV	0.08	2000	
CP201209T-241□	240	100 MHZ,200 mV	0.08	2000	
CP201209T-251□	250	100 MHZ,200 mV	0.08	2000	
CP201209T-301□	300	100 MHZ,200 mV	0.08	2000	
CP201209T-331□	330	100 MHZ,200 mV	0.08	2000	
CP201209T-391□	390	100 MHZ,200 mV	0.1	2000	
CP201209T-401□	400	100 MHZ,200 mV	0.1	2000	
CP201209T-451	450	100 MHZ,200 mV	0.1	2000	
CP201209T-471□	470	100 MHZ,200 mV	0.1	2000	
CP201209T-501□	500	100 MHZ,200 mV	0.1	2000	
CP201209T-601□	600	100 MHZ,200 mV	0.1	2000	
CP201209T-751□	750	100 MHZ,200 mV	0.12	1500	
CP201209T-102	1000	100 MHZ,200 mV	0.12	1500	
CP201209T-152	1500	100 MHZ,200 mV	0.3	1000	





Multilayer Chip Beads / CP TYPE (Large Current) Electrical Characteristics (CP321611 TYPE)

Part No.	IMPEDANCE	Test frequency	DCR	Rate Current	
Fait NO.	(Ω±25%)		(Ω) Max	(mA) Max	
CP321611T-080	8	100 MHZ,200 mV	0.015	6000	
CP321611T-110	11	100 MHZ,200 mV	0.015	6000	
CP321611T-190	19	100 MHZ,200 mV	0.015	6000	
CP321611T-260	26	100 MHZ,200 mV	0.015	6000	
CP321611T-300	30	100 MHZ,200 mV	0.015	4000	
CP321611T-310	31	100 MHZ,200 mV	0.015	4000	
CP321611T-320	32	100 MHZ,200 mV	0.015	4000	
CP321611T-350	35	100 MHZ,200 mV	0.015	4000	
CP321611T-400	40	100 MHZ,200 mV	0.015	4000	
CP321611T-420	42	100 MHZ,200 mV	0.015	4000	
CP321611T-500	50	100 MHZ,200 mV	0.02	4000	
CP321611T-520	52	100 MHZ,200 mV	0.02	4000	
CP321611T-600	60	100 MHZ,200 mV	0.02	4000	
CP321611T-680	68	100 MHZ,200 mV	0.02	4000	
CP321611T-700	70	100 MHZ,200 mV	0.02	4000	
CP321611T-800	80	100 MHZ,200 mV	0.025	3000	
CP321611T-900	90	100 MHZ,200 mV	0.03	3000	
CP321611T-101	100	100 MHZ,200 mV	0.03	2500	
CP321611T-121	120	100 MHZ,200 mV	0.03	2500	
CP321611T-151	150	100 MHZ,200 mV	0.04	2000	
CP321611T-201	200	100 MHZ,200 mV	0.05	2000	
CP321611T-221	220	100 MHZ,200 mV	0.05	2000	
CP321611T-301	300	100 MHZ,200 mV	0.06	2000	
CP321611T-401	400	100 MHz,200 mV	0.1	2000	
CP321611T-501	500	100 MHZ,200 mV	0.1	2000	
CP321611T-601	600	100 MHZ,200 mV	0.1	2000	
CP321611T-102	1000	50 MHZ,200 mV	0.15	1200	
CP321611T-122	1200	50 MHZ,200 mV	0.18	1000	
CP321611T-152	1500	50 MHZ,200 mV	0.2	800	

Electrical Characteristics (CP451616 TYPE)

Part No.	IMPEDANCE	Test frequency	DCR	Rate Current
r art ivo.	(Ω±25%)		(Ω) Max	(mA) Max
CP451616T-190	19	100 MHZ,200 mV	0.02	6000
CP451616T-400	40	100 MHZ,200 mV	0.02	6000
CP451616T-500	50	100 MHZ,200 mV	0.02	6000
CP451616T-600□	60	100 MHZ,200 mV	0.02	5000
CP451616T-700□	70	100 MHZ,200 mV	0.025	5000
CP451616T-750	75	100 MHZ,200 mV	0.025	5000
CP451616T-800□	80	100 MHZ,200 mV	0.025	4000
CP451616T-101□	100	100 MHZ,200 mV	0.1 200	
CP451616T-151	150	100 MHZ,200 mV	0.1	2000





Multilayer Chip Beads / CP TYPE (Large Current) Electrical Characteristics (CP451616 TYPE)

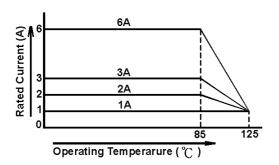
Part No.	IMPEDANCE	Test frequency	DCR	Rate Current
Part No.	(Ω±25%)		(Ω) Max	(mA) Max
CP451616T-191	190	100 MHZ,200 mV	0.1	2000
CP451616T-301□	300	100 MHZ,200 mV	0.1	2000
CP451616T-601□	CP451616T-601☐ 600		0.1	2000
CP451616T-102	1000	100 MHZ,200 mV	0.1	2000
CP451616T-132	1300	100 MHZ,200 mV	0.1	2000

Electrical Characteristics (CP453215 TYPE)

Part No.	IMPEDANCE	Test frequency	DCR	Rate Current	
Fait No.	(Ω±25%)		(Ω) Max	(mA) Max	
CP453215T-190	19	100 MHZ,200 mV	0.03	6000	
CP453215T-300	30	100 MHZ,200 mV	0.03	6000	
CP453215T-470	47	100 MHZ,200 mV	0.03	6000	
CP453215T-500	50	100 MHZ,200 mV	0.03	6000	
CP453215T-600	60	100 MHZ,200 mV	0.03	6000	
CP453215T-700	70	100 MHZ,200 mV	0.03	6000	
CP453215T-800	80	100 MHZ,200 mV	0.03	4000	
CP453215T-900	90	100 MHZ,200 mV	0.03	4000	
CP453215T-121	120	100 MHZ,200 mV	0.03	4000	
CP453215T-125	125	100 MHZ,200 mV	0.03	4000	
CP453215T-151	150	100 MHZ,200 mV	mV 0.03 40		
CP453215T-191□	190	100 MHZ,200 mV	0.03	4000	

NOTE:

- 1. Operating temperature range $-55^{\circ}\text{C} \sim 125^{\circ}\text{C}$
- 2. Rate Current: Applied the current to coils, the temperature rise shall not be more than 30°C
- 3. Rate Current is deRate as left figure depending on the operating temprature.
- 4. □Tolerance : J=5% ; K=10% ; M=20% ; Y=25% ; N=30%







☑. Reliability and Test Conditions(可靠性測試條件) 1-1.Mechanical Performance

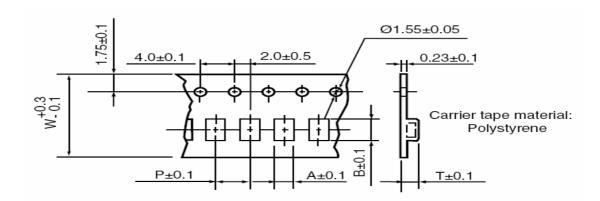
Item	Specification	Test Method		
Flexure Strength	The forces applied on the right	Test device shall be soldered on the substrate		
	conditions must not damage	Substrate Dimension: 100x40x1.6mm		
	the terminal electrode and the	Deflection: 2.0mm		
	ferrite	Keeping Time: 30sec		
		*For 100505, substrate dimension is 100x40x0.8mm		
Vibration		Test device shall be soldered on the substrate		
		Oscillation Frequency: 10 to 55 to 10Hz for 1min		
		Amplitude: 1.5mm		
		Time: 2hrs for each axis (X, Y & Z), total 6hrs		
Resistance to Soldering Heat	Appearance: No damage	Pre-heating: 150°C, 1min		
	More than 75% of the terminal	Solder Composition: Sn/Pb = 63/37		
	electrode should be covered	Solder Composition: Sn/Ag3.0/Cu0.5(Pb-Free)		
	with solder. Impedance:	Solder Temperature: 260±5°C		
	within ±30% of initial value	Immersion Time: 10±1sec		
Solder ability	The electrodes shall be at	Pre-heating: 150°C, 1min		
	least 90% covered with new	Solder Composition: Sn/Pb = 63/37		
	solder coating	Solder Temperature: 220±5°C		
		Solder Composition: Sn/Ag3.0/Cu0.5(Pb-Free)		
		Solder Temperature: 245±5°C (Pb-Free)		
		Immersion Time: 4±1sec		
Terminal Strength Test	100505 series : ≥ 0.2 kg	Test device shall be soldered on the substrate		
	160808 series : ≧ 0.5 kg			
	201209 series : ≧ 1.0 kg			
	other series : \geq 2.0 kg	\(\)		
	BAY/BAQ321609 series:≧ 1.5 kg	==1		
	(Push)			

Item	Specification	Test Method				
Temperature Cycle	Appearance: No damage	One c	One cycle:			
	Impedance: within±30% of	Step	Temperature (°C)	Time (min)		
	initial value	1	-55±3	30		
		2	25±2	3		
		3	125±3	30		
		4	25±2	3		
		Total:	100cycles			
		Measu	ıred after exposure ir	n the room con	dition for 24hrs	
Humidity Resistance		Tempe	erature: 40±2°C			
		Relative Humidity: 90 ~ 95% / Time: 1000hrs				
		Measured after exposure in the room condition for 24h				
High		Tempe	erature: 125±3°C / Re	elative Humidity	/ : 0%	
Temperature Resistance		Applie	d Current: Rated Cu	rrent /Time: 100	00hrs	
		Measured after exposure in the room condition for 24hrs				
Low		Temperature: -55±3°C				
Temperature Resistance		Relativ	e Humidity: 0% / Tir	ne: 1000hrs		
		Measu	ıred after exposure ir	n the room con	dition for 24hrs	

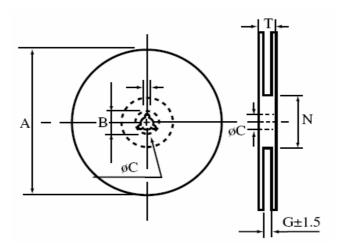




.Packing Specifications



TYPE	Packagin	g Quantity	Tape Dimension				
IIFE	Pcs / Reel	Inner box	Α	В	W	Р	Т
CP160808	4000	20000	1.08	1.88	8	4	1.05
CP201209	4000	20000	1.42	2.24	8	4	1.04
CP321611	3000	15000	1.88	3.5	8	4	1.27
CP451616	2000	8000	1.93	4.95	12	4	1.93
CP453215	1000	4000	3.66	4.95	12	8	1.83



TYPE	Reel Dimension					
ITPE	Α	В	С	G	N	Т
8mm	178±2	21.0±0.8	13.0±0.8	10	75	12.5
12mm	178±2	21.0±0.8	13.0±0.8	14	75	16.5









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EROCORE ENTERPRISE CO., LTD.
16F, NO. 700, JHONGJHENG RD., JHONGHE CITY, TAIPEI COUNTY 23552, TAIWAN (R. O. C.)

The following sample(s) was/were submitted and identified by/on behalf of the client as :

Sample Description : FERRITE CHIP BEAD, INDUCTOR, ARRAY Style/Item No. : FERRITE CHIP BEAD, INDUCTOR, ARRAY

Sample Receiving Date : 2007/06/11

Testing Period : 2007/06/11 TO 2007/06/20

Test Result(s) : Please refer to next page(s).

Shin - Jyh Chen Shinjyh Chen / Asst. Manager Signed for and on behalf of SGS TAIWAN LTD. Chemical Laboratory - Taipei







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EROCORE ENTERPRISE CO., LTD. 16F, NO. 700, JHONGJHENG RD., JHONGHE CITY, TAIPEI COUNTY 23552, TAIWAN (R. O. C.)

Test Result(s)

PART NAME NO.1 MIXED ALL PARTS

Test Item (s):	Unit	Method	MDL	Result
				No.1
Halogen		With reference to prEN14582 method B. Analysis was performed by IC method for F, CI, Br, I content.		
Halogen-Chlorine (CI) (CAS No.: 007782-50-5)	mg/kg	With reference to prEN14582 method B. Analysis was performed by IC method for Chlorine content.	50	n.d.
Halogen-Fluorine (F) (CAS No.: 007782-41-4)	mg/kg	With reference to prEN14582 method B. Analysis was performed by IC method for Fluorine content.	50	n.d.
Halogen-Bromine (Br) (CAS No.: 007726-95-6)	mg/kg	With reference to prEN14582 method B. Analysis was performed by IC method for Bromine content.	50	n.d.
Halogen-lodine (I) (CAS No.: 007553-56-2)	mg/kg	With reference to prEN14582 method B. Analysis was performed by IC method for lodine content.	50	n.d.

Note: 1. mg/kg = ppm

2. n.d. = Not Detected

3. MDL = Method Detection Limit

4. "---" = Not Conducted

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SGS TAIWAN LIMITED No. 13e-1, Wu Kung Road, WuKu Industrial Zone, Taipei county, Taiwan. (1886-2) 22993939 f(886-2) 2299-3237 www.sgs.com.tw





Multilayer Chip Beads / CP TYPE (Large Current)



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EROCORE ENTERPRISE CO., LTD. 16F, NO. 700, JHONGJHENG RD., JHONGHE CITY, TAIPEI COUNTY 23552, TAIWAN (R. O. C.)



** End of Report **







Test Report No.: CE/2007/36683G Date: 2007/07/12 Page : 1 of 5

EROCORE ENTERPRISE CO., LTD. 16F, NO. 700, JHONGJHENG RD., JHONGHE CITY, TAIPEI COUNTY 23552, TAIWAN (R. O. C.)

The following sample(s) was/were submitted and identified by/on behalf of the client as:

Sample Description FERRITE CHIP BEAD, INDUCTOR, ARRAY Style/Item No. FERRITE CHIP BEAD, INDUCTOR, ARRAY

Sample Receiving Date 2007/03/22

Testing Period 2007/03/22 TO 2007/03/29

: In accordance with the RoHS Directive 2002/95/EC, and its Test Requested

amendment directives.

Test Method With reference to IEC 62321, Ed.1 111/54/CDV

Procedures for the Determination of Levels of Regulated Substances

in Electrotechnical Products.

Determination of Cadmium by ICP-AES. (1)

(2) Determination of Lead by ICP-AES.

Determination of Mercury by ICP-AES. (3)

Determination of Hexavalent Chromium for non-metallic (4)

samples by UV/Vis Spectrometry.

Determination of PBB and PBDE by GC/MS.

Test Result(s) Please refer to next page(s).

Deration Manager Signed for and on behalf of SGS TAIWAN LTD.







Test Report No.: CE/2007/36683G Date: 2007/07/12 Page: 2 of 5

EROCORE ENTERPRISE CO., LTD. 16F, NO. 700, JHONGJHENG RD., JHONGHE CITY, TAIPEI COUNTY 23552, TAIWAN (R. O. C.)

Test results by chemical method (Unit: mg/kg)

T4 H (-)-	Method	Result		
Test Item (s):	(Refer to)	No.1	MDL	
Cadmium (Cd)	(1)	n.d.	2	
Lead (Pb)	(2)	29	2	
Mercury (Hg)	(3)	n.d.	2	
Hexavalent Chromium Cr(VI) by alkaline extraction	(4)	n.d.	2	
Sum of PBBs		n.d.	-	
Monobromobiphenyl	l t	n.d.	5	
Dibromobiphenyl	Ī	n.d.	5	
Tribromobiphenyl		n.d.	5	
Tetrabromobiphenyl		n.d.	5	
Pentabromobiphenyl	Ī	n.d.	5	
Hexabromobiphenyl	1	n.d.	5	
Heptabromobiphenyl	1	n.d.	5	
Octabromobiphenyl		n.d.	5	
Nonabromobiphenyl		n.d.	5	
Decabromobiphenyl		n.d.	5	
Sum of PBDEs (Mono to Nona) (Note 4)	(5)	n.d.	-	
Monobromobiphenyl ether		n.d.	5	
Dibromobiphenyl ether		n.d.	5	
Tribromobiphenyl ether		n.d.	5	
Tetrabromobiphenyl ether		n.d.	5	
Pentabromobiphenyl ether		n.d.	5	
Hexabromobiphenyl ether		n.d.	5	
Heptabromobiphenyl ether		n.d.	5	
Octabromobiphenyl ether		n.d.	5	
Nonabromobiphenyl ether		n.d.	5	
Decabromobiphenyl ether		n.d.	5	
Sum of PBDEs (Mono to Deca)	[n.d.	-	

TEST PART DESCRIPTION:

MIXED ALL PARTS

Note: 1. mg/kg = ppm

2. n.d. = Not Detected

3. MDL = Method Detection Limit

4. According to 2005/717/EC DecaBDE is exempt.

5. "-" = Not Regulated

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SGS TAIWAN LIMITED

NO. 138-1, Wu Kung Road, WuKu Industrial Zone, Taipei county, Taiwan.

t(888-2) 22993939 f(886-2) 2299-3237 www.sgs.com.tw



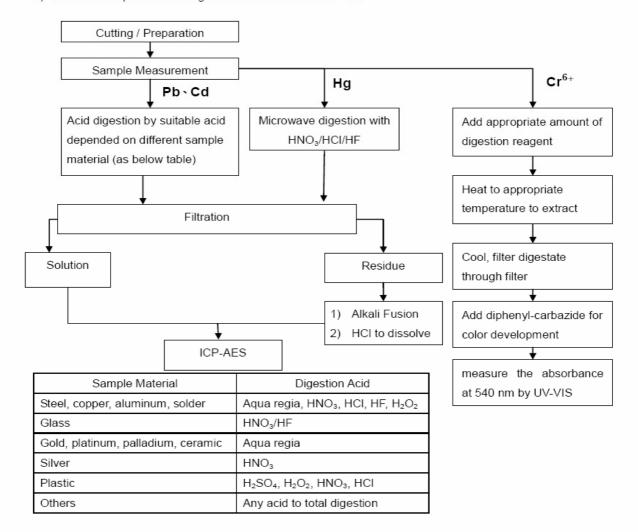




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EROCORE ENTERPRISE CO., LTD. 16F, NO. 700, JHONGJHENG RD., JHONGHE CITY, TAIPEI COUNTY 23552, TAIWAN (R. O. C.)

- 1) These samples were dissolved totally by pre-conditioning method according to below flow chart. (Cr6+ test method excluded)
- 2) Name of the person who made measurement: Troy Chang
- 3) Name of the person in charge of measurement: Daniel Yeh



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SGS TAIWAN LIMITED

NO. 136-1, Wu Kung Road, Wu Ku Industrial Zone, Taipei county, Taiwan.

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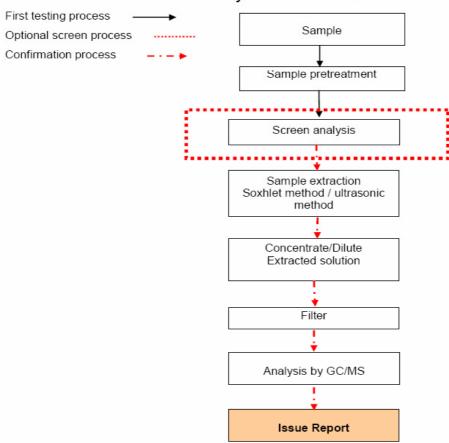


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PBB/PBDE analytical FLOW CHART



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** End of Report **